



# ACE4614B

## 30V Complementary Enhancement Mode Field Effect Transistor

### Description

The ACE4614B uses advanced trench technology MOSFETs to provide excellent  $R_{DS(ON)}$  and low gate charge. The complementary MOSFETs may be used in inverter and other applications.

### Features

N-channel

- $V_{DS}=30V$
- $I_D=9A$
- $R_{DS(ON)}<14m\Omega(V_{GS}=10V)$
- $R_{DS(ON)}<22m\Omega(V_{GS}=4.5V)$

P-channel

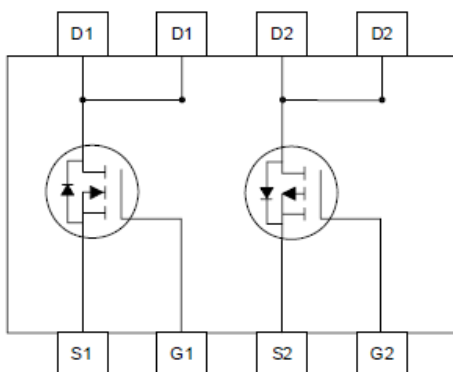
- $V_{DS}=-30V$
- $I_D=-8A$
- $R_{DS(ON)}<20m\Omega(V_{GS}=-10V)$
- $R_{DS(ON)}<35m\Omega(V_{GS}=-4.5V)$

### Absolute Maximum Ratings

Parameter	Symbol	N-channel	P-channel	Unit	
Drain-Source Voltage	$V_{DSS}$	30	-30	V	
Gate-Source Voltage	$V_{GSS}$	$\pm 20$	$\pm 20$	V	
Drain Current (Continuous) * AC	$I_D$	$T_A=25^\circ C$	9	-8	A
		$T_A=70^\circ C$	7.2	-6.4	
Drain Current (Pulse) * B	$I_{DM}$	40	-40		
Power Dissipation	$P_D$	$T_A=25^\circ C$	2	2	W
		$T_A=70^\circ C$	1.3	1.3	
Operating and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	-55 to 150	$^\circ C$	

### Packaging Type

SOP-8



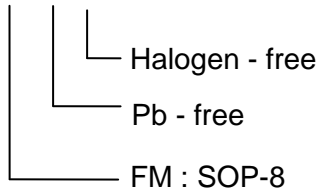


# ACE4614B

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### Ordering information

ACE4614B XX + H



### N-channel Electrical Characteristics $T_A=25^\circ\text{C}$ unless otherwise noted

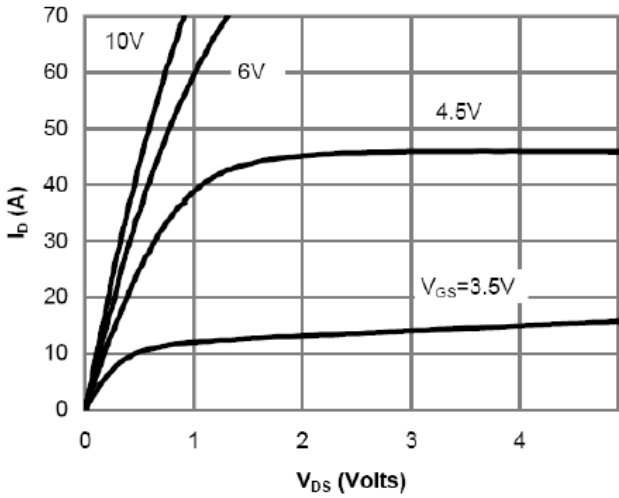
Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=250\mu A$	30			V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=30V, V_{GS}=0V$			1	$\mu A$
Gate Leakage Current	$I_{GSS}$	$V_{GS}=\pm 20V, V_{DS}=0V$			100	nA
Static Drain-Source On-Resistance	$R_{DS(ON)}$	$V_{GS}=10V, I_D=10A$		12	14	m $\Omega$
		$V_{GS}=4.5V, I_D=10A$		16.5	22	
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=250\mu A$	1.4	2	3	V
Forward Transconductance	$g_{FS}$	$V_{DS}=5V, I_D=10A$		20		S
Diode Forward Voltage	$V_{SD}$	$I_{SD}=1A, V_{GS}=0V$		0.74	1.0	V
Maximum Body-Diode Continuous Current	$I_S$				2.6	A
Switching						
Total Gate Charge	$Q_g$	$V_{DS}=15V, I_D=10A$ $V_{GS}=5V$		7.65	9.95	nC
Gate-Source Charge	$Q_{gs}$			2.82	3.67	
Gate-Drain Charge	$Q_{gd}$			2.49	3.24	
Turn-On Delay Time	$T_{d(on)}$	$V_{DS}=15V, R_{GEN}=6\Omega,$ $V_{GS}=10V$ $R_L=15\Omega$		13.92	27.84	ns
Turn-On Rise Time	$t_f$			2.64	5.28	
Turn-Off Delay Time	$t_{d(off)}$			31.4	62.8	
Turn-Off Fall Time	$t_f$			3.28	6.56	
Dynamic						
Input Capacitance	$C_{iss}$	$V_{DS}=15V, V_{GS}=0V$ $f=1\text{MHz}$		886.01		pF
Output Capacitance	$C_{oss}$			151		
Reverse Transfer Capacitance	$C_{rss}$			75.77		

Note.

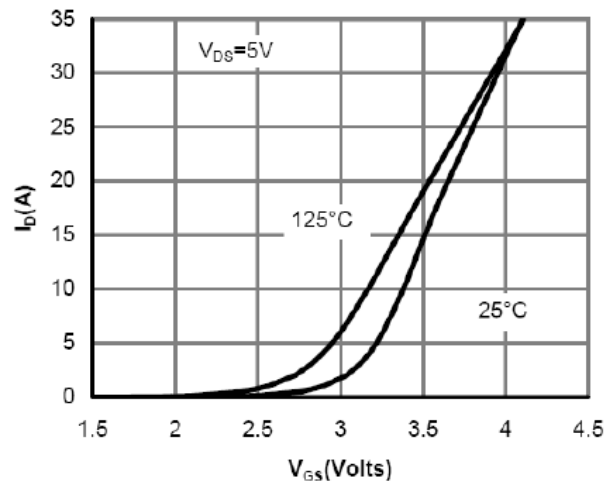
- The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.
- Repetitive rating, pulse width limited by junction temperature.
- The current rating is based on the  $t \leq 10s$  junction to ambient thermal resistance rating.



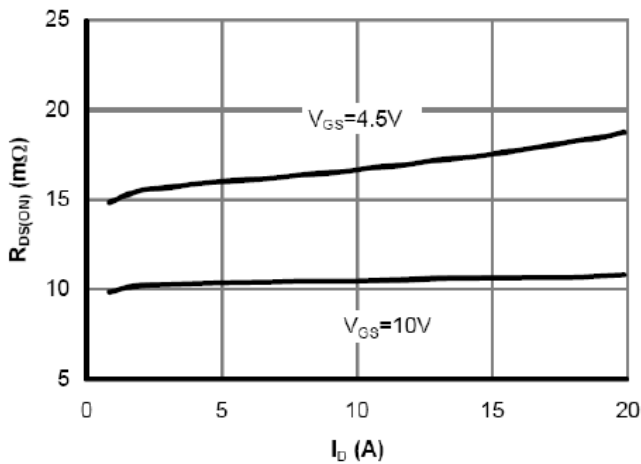
**Typical Performance Characteristics**



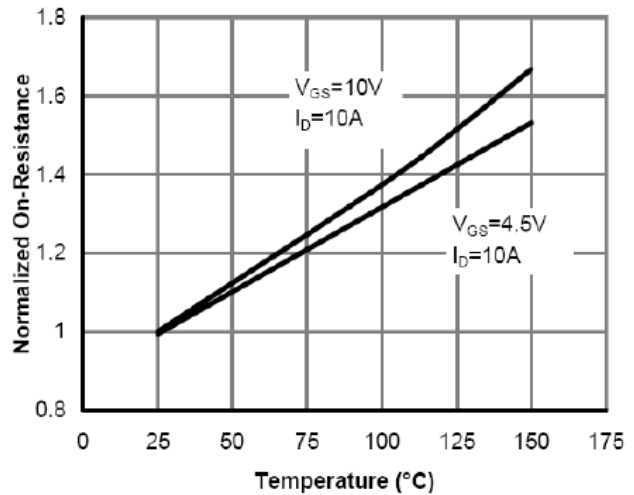
**Fig 1: On-Region Characteristics**



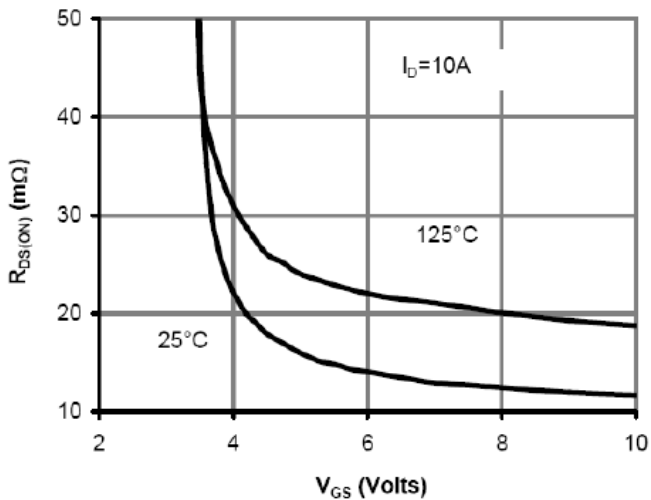
**Figure 2: Transfer Characteristics**



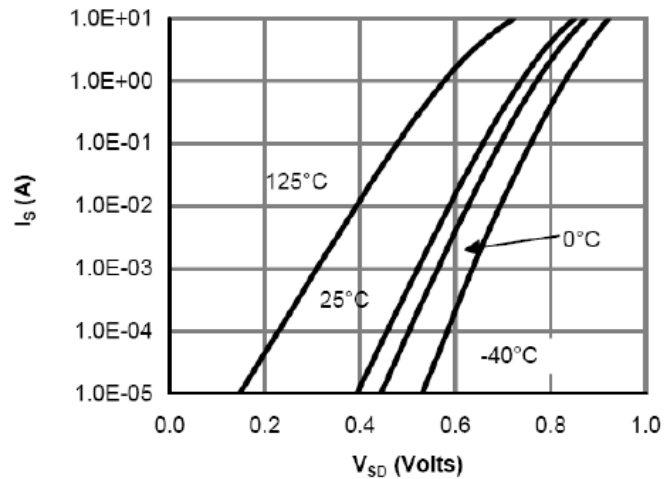
**Figure 3: On-Resistance vs. Drain Current and Gate Voltage**



**Figure 4: On-Resistance vs. Junction Temperature**



**Figure 5: On-Resistance vs. Gate-Source Voltage**



**Figure 6: Body-Diode Characteristics**



Typical Performance Characteristics

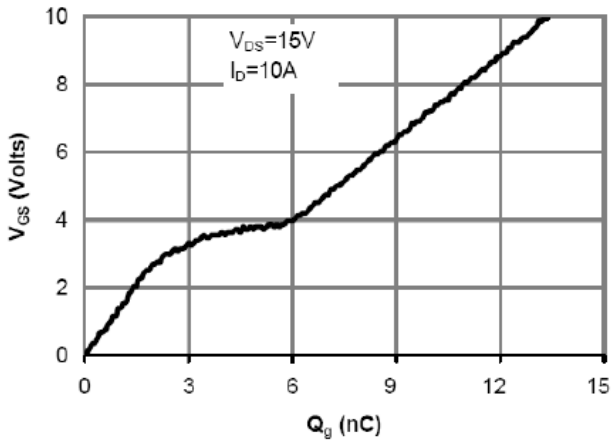


Figure 7: Gate-Charge Characteristics

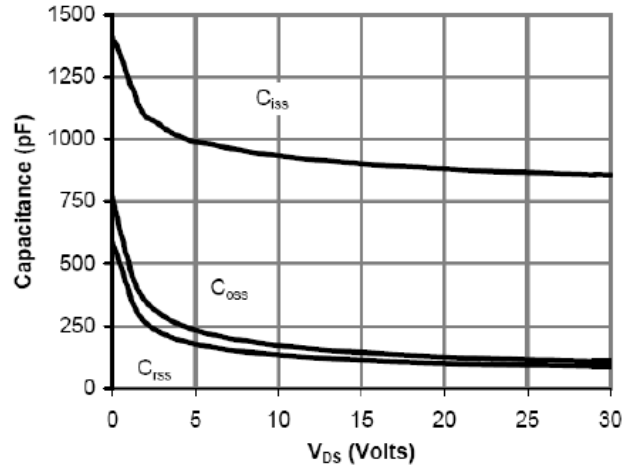


Figure 8: Capacitance Characteristics

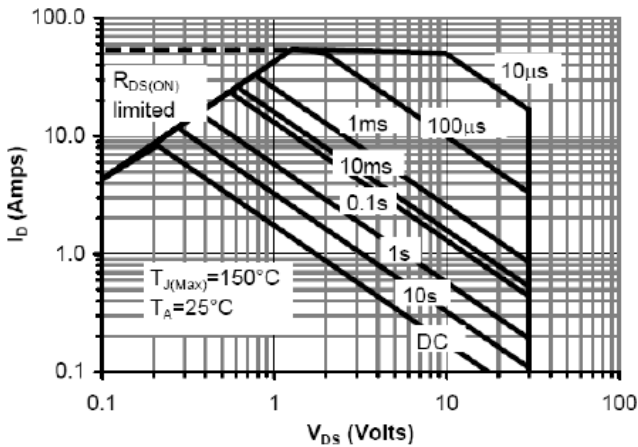


Figure 9: Maximum Forward Biased Safe Operating Area

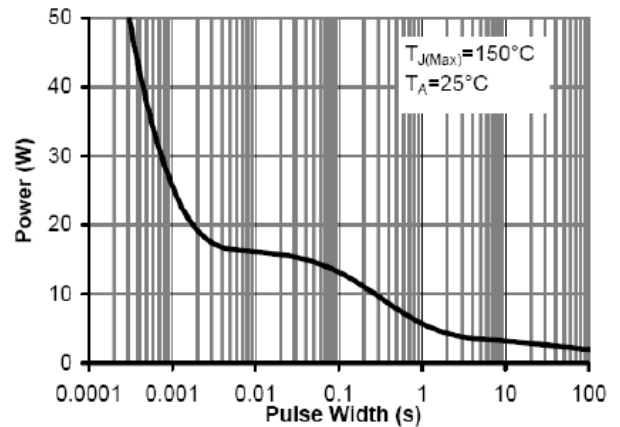


Figure 10: Single Pulse Power Rating Junction-to-Ambient

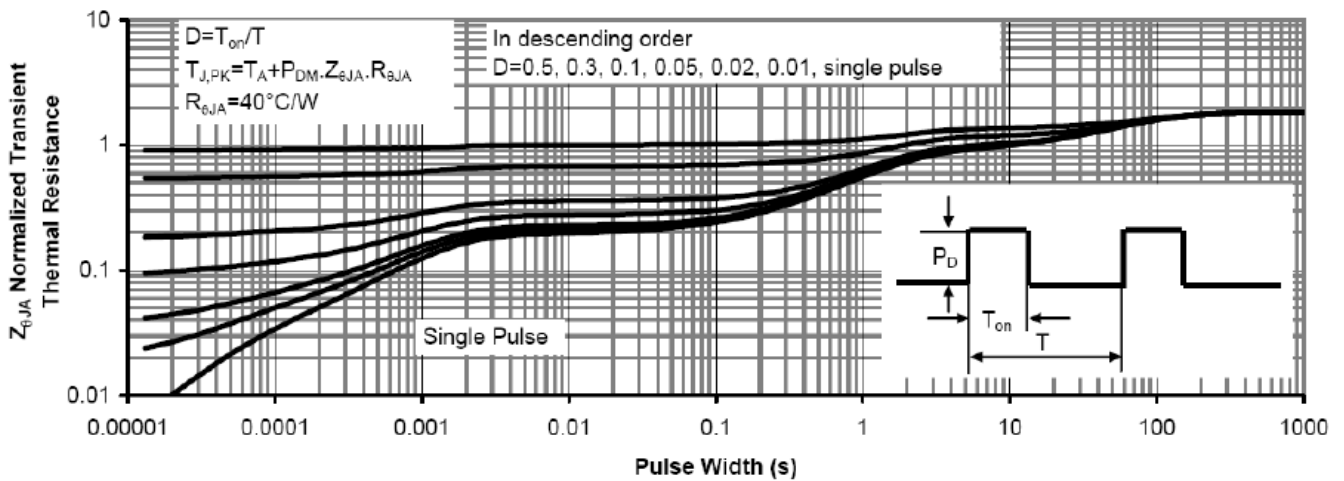


Figure 11: Normalized Maximum Transient Thermal Impedance



# ACE4614B

## 30V Complementary Enhancement Mode Field Effect Transistor

### P-channel Electrical Characteristics $T_A=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Conditions	Min.	Typ.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS}=0V, I_D=-250\mu A$	-30			V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=-30V, V_{GS}=0V$			-1	$\mu A$
Gate Leakage Current	$I_{GSS}$	$V_{GS}=\pm 20V, V_{DS}=0V$			100	nA
Static Drain-Source On-Resistance	$R_{DS(ON)}$	$V_{GS}=-10V, I_D=-9.7A$		17.1	20	m $\Omega$
		$V_{GS}=-4.5V, I_D=-7A$		20.7	35	
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=-250\mu A$	-1	-1.2	-2	V
Forward Transconductance	$g_{FS}$	$V_{DS}=-5V, I_D=-8A$		21.7		S
Diode Forward Voltage	$V_{SD}$	$I_{SD}=-1A, V_{GS}=0V$		-0.74	-1.0	V
Maximum Body-Diode Continuous Current	$I_S$				-2.1	A
Switching						
Total Gate Charge	$Q_g$	$V_{DS}=-15V, I_D=-8A$ $V_{GS}=-10V$		33.82	43.97	nC
Gate-Source Charge	$Q_{gs}$			4.93	6.41	
Gate-Drain Charge	$Q_{gd}$			5.2	6.76	
Turn-On Delay Time	$T_{d(on)}$	$V_{DS}=-15V, R_{GEN}=6\Omega,$ $V_{GS}=-10V$ $R_L=15\Omega$		15.44	30.88	ns
Turn-On Rise Time	$t_f$			5.04	10.08	
Turn-Off Delay Time	$t_{d(off)}$			71.04	142.08	
Turn-Off Fall Time	$t_f$			16.8	33.6	
Dynamic						
Input Capacitance	$C_{iss}$	$V_{DS}=-15V, V_{GS}=0V$ $f=1MHz$		1973	2200	pF
Output Capacitance	$C_{oss}$			491		
Reverse Transfer Capacitance	$C_{rss}$			231	325	

Note.

- The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ\text{C}$ . The value in any given application depends on the user's specific board design.
- Repetitive rating, pulse width limited by junction temperature.
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### Typical Performance Characteristics

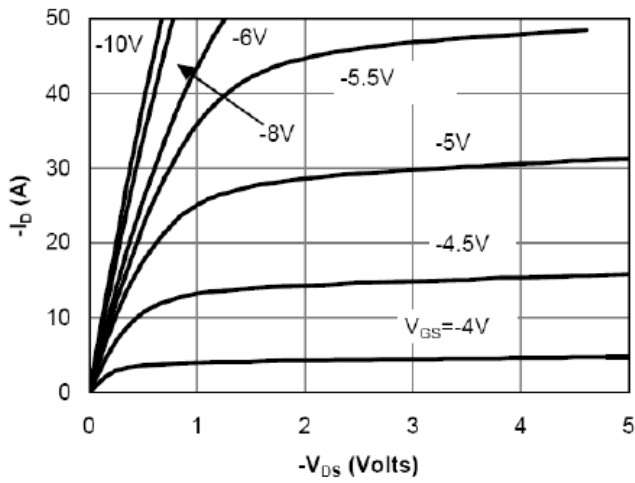


Fig 1: On-Region Characteristics

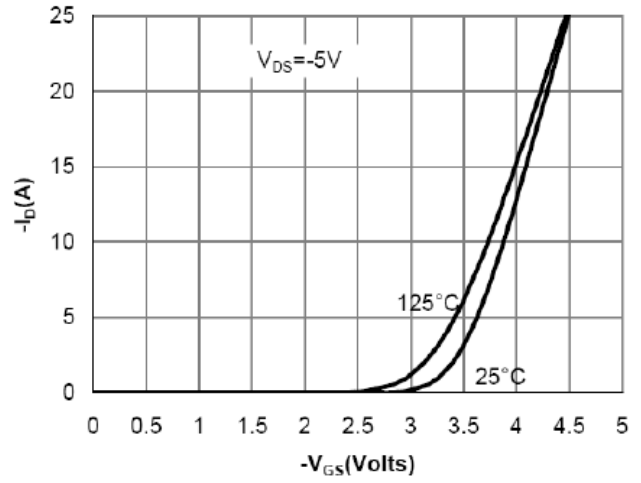


Figure 2: Transfer Characteristics

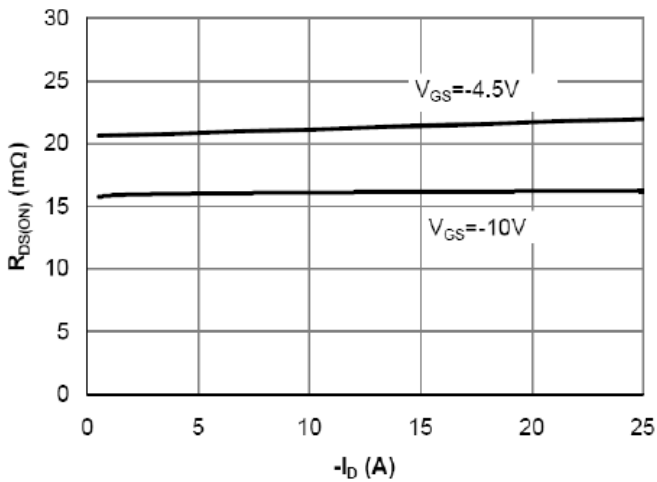


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

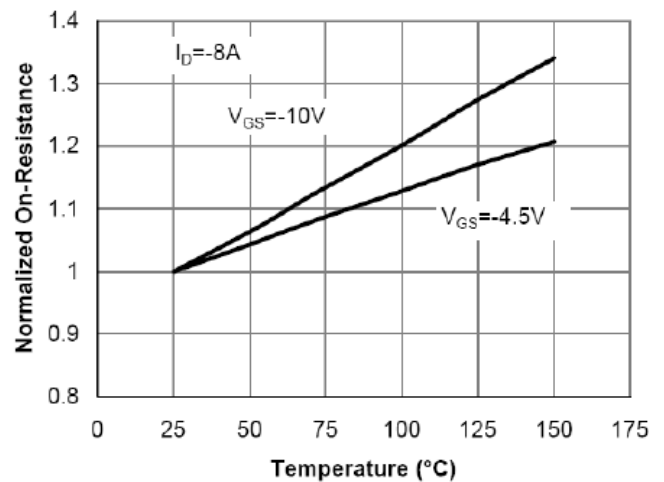


Figure 4: On-Resistance vs. Junction Temperature

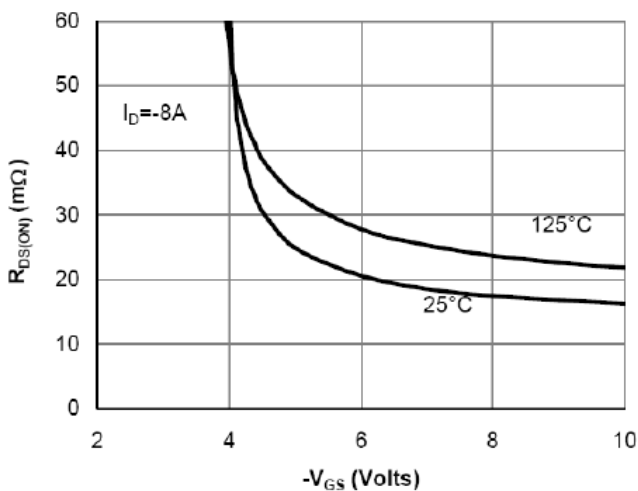


Figure 5: On-Resistance vs. Gate-Source Voltage

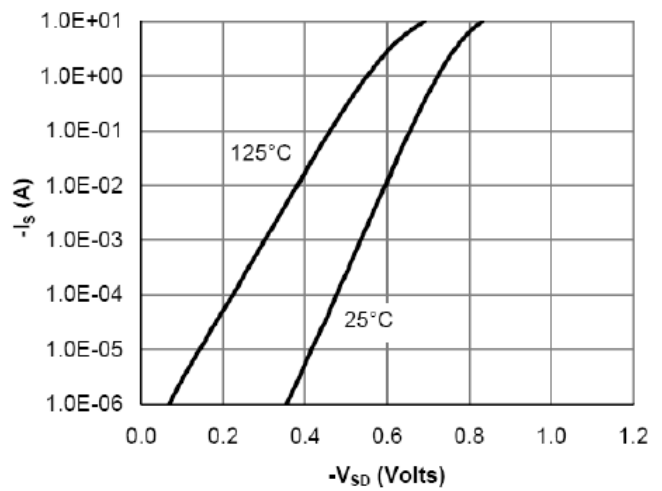


Figure 6: Body-Diode Characteristics



Typical Performance Characteristics

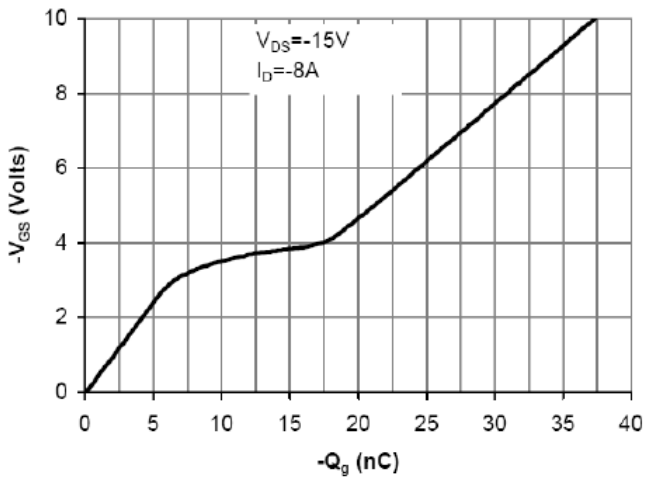


Figure 7: Gate-Charge Characteristics

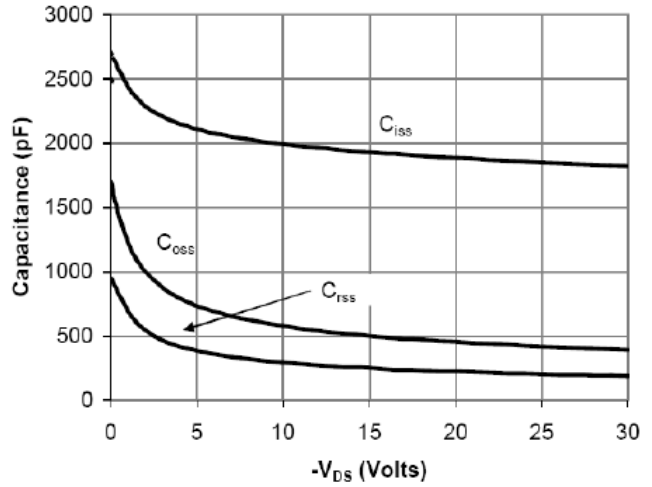


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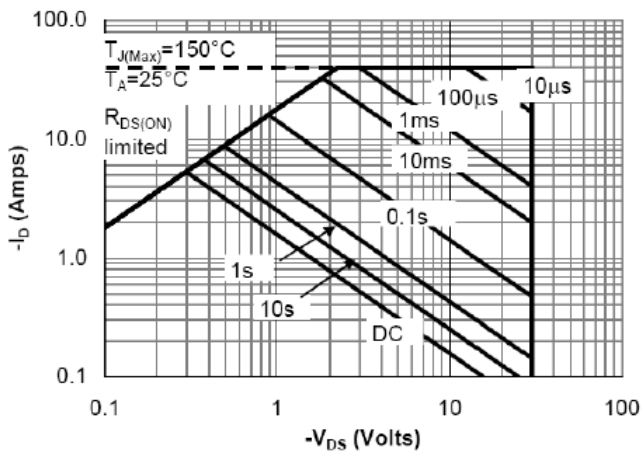


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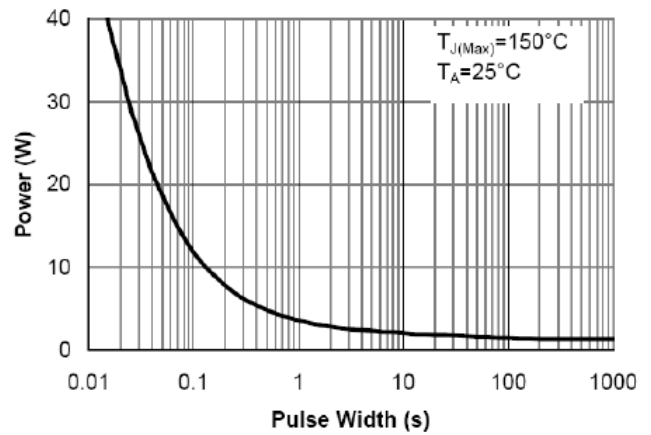


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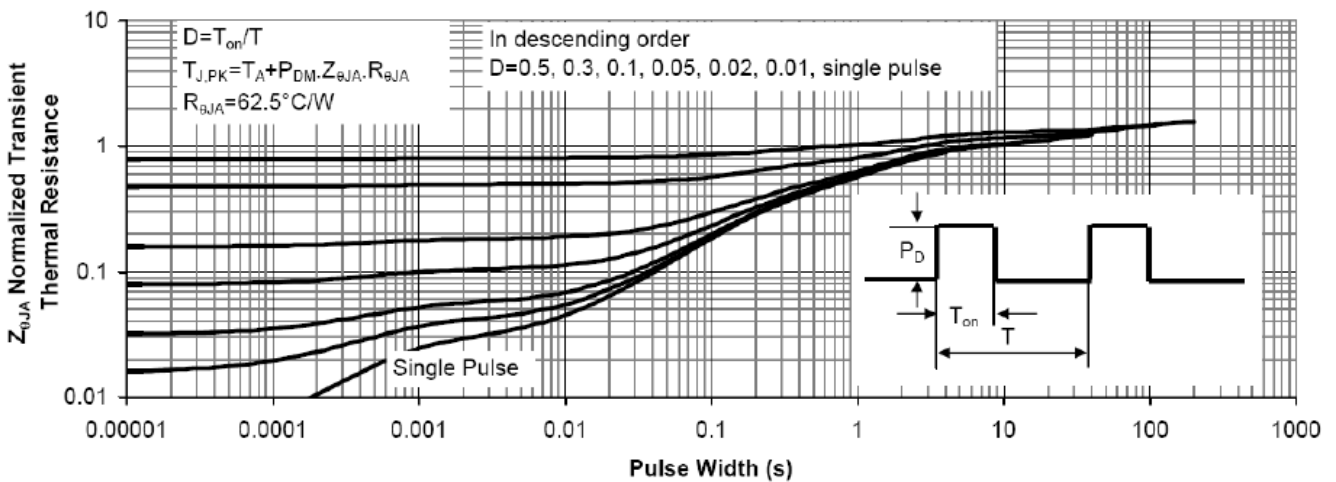


Figure 11: Normalized Maximum Transient Thermal Impedance

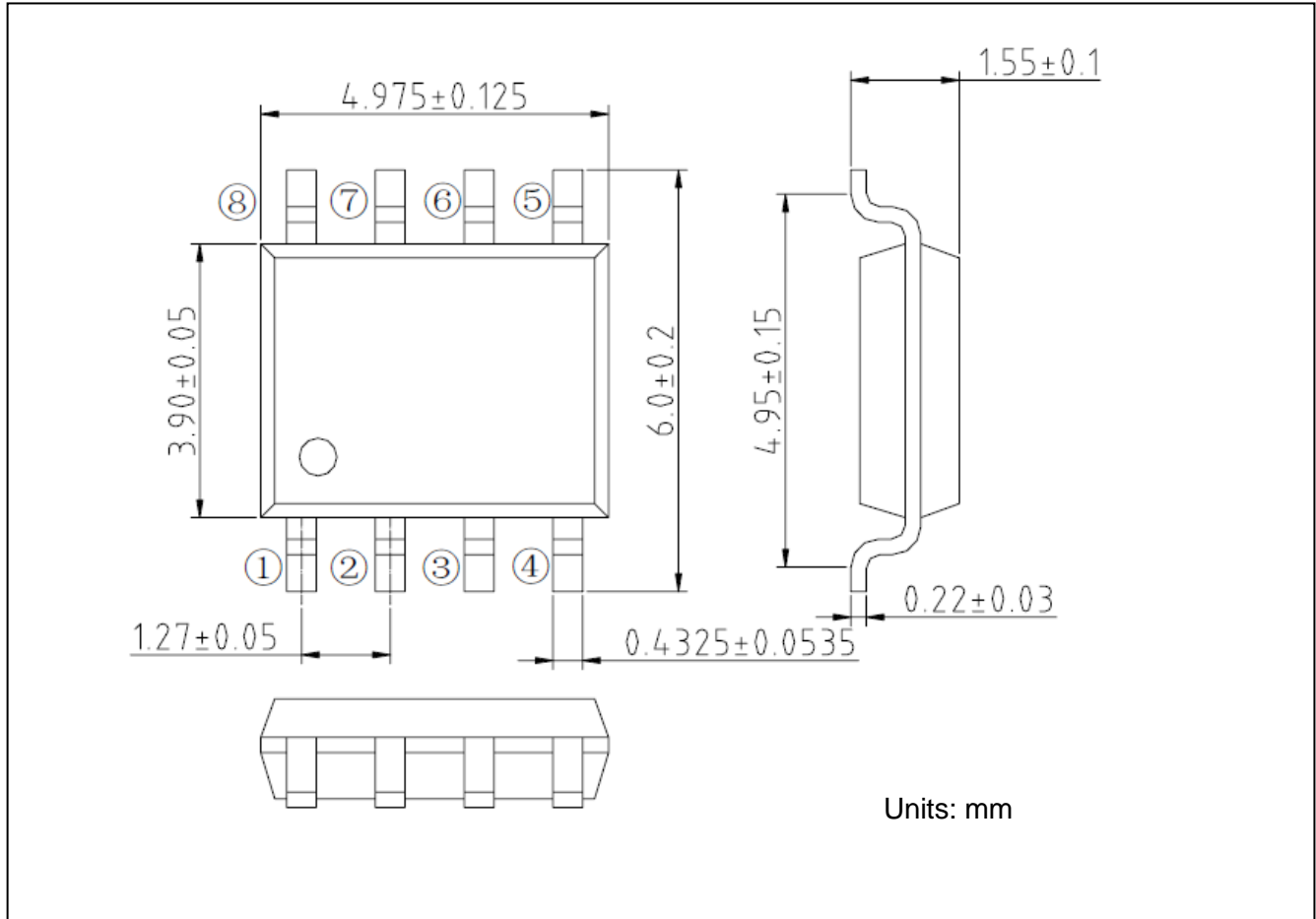


# ACE4614B

## 30V Complementary Enhancement Mode Field Effect Transistor

### Packing Information

#### SOP-8







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### Notes

ACE does not assume any responsibility for use as critical components in life support devices or systems without the express written approval of the president and general counsel of ACE Electronics Co., LTD. As sued herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury to the user.
2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

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